

CONTENTS

PREFATORY

- What Next for Departments of Materials Science and Engineering?
M. C. Flemings 1

SCANNING PROBES

- Magnetic Force Microscopy, *U. Hartmann* 53
Scanning SQUID Microscopy, *John R. Kirtley and
John P. Wikswo, Jr.* 117
Kelvin Probe Force Microscopy of Molecular Surfaces, *M. Fujihira* 353
Characterization of Organic Thin Film Materials with Near-Field
Scanning Optical Microscopy (NSOM), *P. F. Barbara,
D. M. Adams, and D. B. O'Connor* 433
Two-Dimensional Dopant Profiling by Scanning Capacitance
Microscopy, *C. C. Williams* 471
Scanning Thermal Microscopy, *A. Majumdar* 505

CURRENT INTEREST

- Modern Resonant X-Ray Studies of Alloys: Local Order and
Displacements, *G. E. Ice and C. J. Sparks* 25
Skutterudites: A Phonon-Glass-Electron-Crystal Approach to
Advanced Thermoelectric Materials Research, *G. S. Nolas,
D. T. Morelli, and Terry M. Tritt* 89
Combinatorial Materials Synthesis and Screening: An Integrated
Materials Chip Approach to Discovery and Optimization of
Functional Materials, *X.-D. Xiang* 149
Surface Roughening of Heteroepitaxial Thin Films, *Huajian Gao
and William D. Nix* 173
Nanocrystalline Diamond Films, *Dieter M. Gruen* 211
Heat Conduction in Novel Electronic Films, *Kenneth E. Goodson
and Y. Sungtaek Ju* 261

(continued) vii

Applications of Ultrasound to Materials Chemistry, <i>Kenneth S. Suslick and Gareth J. Price</i>	295
Electrophoretic Deposition of Materials, <i>Omer O. Van der Biest and Luc J. Vandeperre</i>	327
Spin-Tunneling in Ferromagnetic Junctions, <i>Jagadeesh S. Moodera, Joaquim Nassar, and George Mathon</i>	381
INDEXES	
Subject Index	587
Cumulative Index of Contributing Authors, Volumes 25–29	607
Cumulative Index of Chapter Titles, Volumes 25–29	609